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Application No. <u>09/362,200</u>	Prepared by <u>NPB</u>	Tracking Number <u>85886243</u>	
Examiner-GAU <u>EC/KRT - 2815</u>	Date <u>2/11/04</u>	Week Date <u>1/5/04</u>	
	No. of queries <u>2</u>	<u>1FW</u>	

## JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

## SPECIFICATION

- a. Page Missing
- b. Text Continuity
- c. Holes through Data
- d. Other Missing Text
- e. Illegible Text
- f. Duplicate Text
- g. Brief Description
- h. Sequence Listing
- i. Appendix
- j. Amendments
- k. Other

## CLAIMS

- a. Claim(s) Missing
- b. Improper Dependency
- c. Duplicate Numbers
- d. Incorrect Numbering
- e. Index Disagrees
- f. Punctuation
- g. Amendments
- h. Bracketing
- i. Missing Text
- j. Duplicate Text
- k. Other

## MESSAGE

① PTO-1449: other documents: Please either initial or line through citations. (copy provided for reference - please see attached).

② Bottom page of drawing pages 13 and 21 (FIGS. 18 and 29) are cut-off. please supply new page. (copy provided for reference - please see attached)

Thankyou

initials mm.

## RESPONSE

initials

FORM PTO-1449  
INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT(S)

Sheet 2 of 2

#C9/362,100

Atty Docket No. : 2369/23  
Serial No. :  
Applicants : K. NAKAZATO et al.  
Filed :  
Group Art Unit :  
Examiner :

**OTHER DOCUMENTS**  
(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner  
Initial

- \_\_\_\_\_ 3. PHYSICAL REVIEW, B. CONDENSED-MATTER, Vol. 50, No. 12, 15 Sept. 1994, pp. 8961-8964, Bar-Sadeh et al.: *Single-Electron Tunneling Effects in Granular Metal Films*
- \_\_\_\_\_ 4. IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 41, No. 9, Sept. 1994, pp. 1628-1638, K. Yano et al.: *Room-Temperature Single-Electron Memory*
- \_\_\_\_\_ 5. 1996 IEEE INTERNATIONAL SOLID-STATE CIRCUITS CONFERENCE, pp. 266-268, K. Yano et al.: *Single-Electron-Memory Integrated Circuit for Giga-to-Tera Bit Storage*
- \_\_\_\_\_ 6. APPL. PHYS. LETT. 68 (10), 4 March 1996, pp. 1377-1379, Sandip Tiwan et al.: *A Silicon Nanocrystals-based Memory*
- \_\_\_\_\_ 7. IEEE ELECTRON DEVICE LETTERS, Vol. EDL 1, No. 9, September 1980, pp. 179-181, DiMaria et al.: *Electrically-Alterable Memory Using A Dual Electron Injector Structure*

EXAMINER

DATE CONSIDERED

K. Nakazato et al.

10/6/01

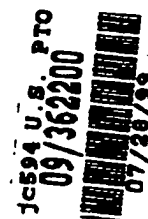
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FORM PTO-1449  
INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT(S)

Sheet 1 of 2

Atty Docket No.: 2369/23  
Serial No.:  
Applicants : K. NAKAZATO et al.  
Filed :  
Group Art Unit:  
Examiner :



U.S. PATENT DOCUMENTS

Examiner Initial	Patent Number	Patent Date	Name	Class/ Subclass	Filing Date
<u>EO</u>	3,878,549	04/15/75	YAMAZAKI et al.	357/23	09/11/73
<u>EO</u>	5,604,357	02/97	HORI	257/324	
<u>EO</u>	5,286,994	02/94	OZAWA et al.	257/324	
<u>EO</u>	5,319,229	06/94	SHIMOJI et al.	257/324	
<u>EO</u>	5,216,262	06/93	TSU	257/411	

FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class/ Subclass	Translation Yes No
<u>EO</u>	2 111 866	06/09/72	France		ABS.
<u>EO</u>	0 842 173	03/08/95	EPO		N/A
<u>EO</u>	WO 94/15340	07/07/94	Great Britain		N/A

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner  
Initial

1. IEEE TRANSACTIONS ON ELECTRON DEVICES, Vol. 43, No. 9, Sept. 1996, pp. 1553-1558, Hanati et al.; *Fast and Long Retention-Time Nano-Crystal Memory*
2. MICROELECTRONIC ENGINEERING, Vol. 32, No. 1/04, Sept. 1996, pp. 297-315, H. Ahmed et al.: *Single-Electron Devices*

EXAMINER

DATE CONSIDERED

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10/4/01

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APPROVED	O.G. FIG.	
BY	CLASS	SUBCLASS
DRAFTSMAN		

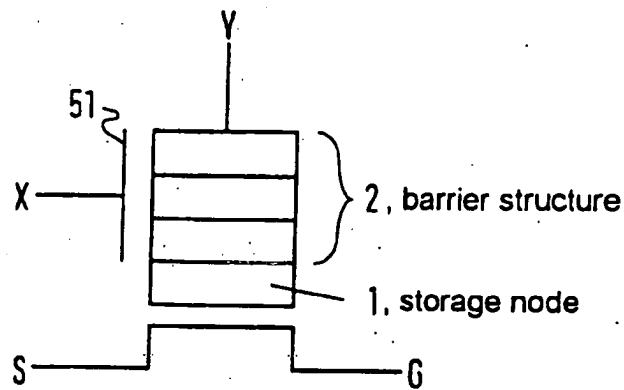
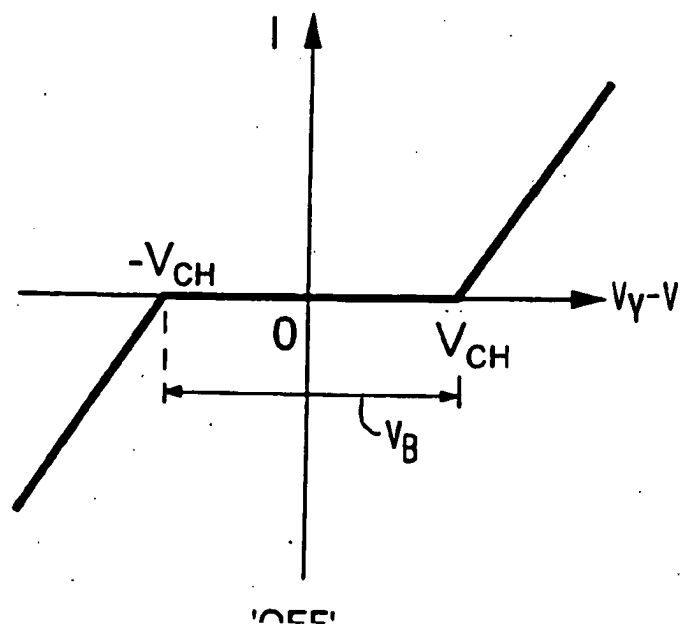
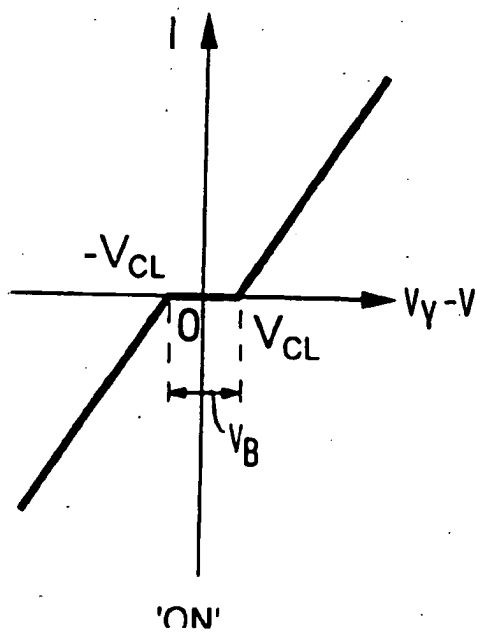


FIG. 17



APPROVED	O.G. FIG.	
BY	CLASS	SUBCLASS
DRAFTSMAN		

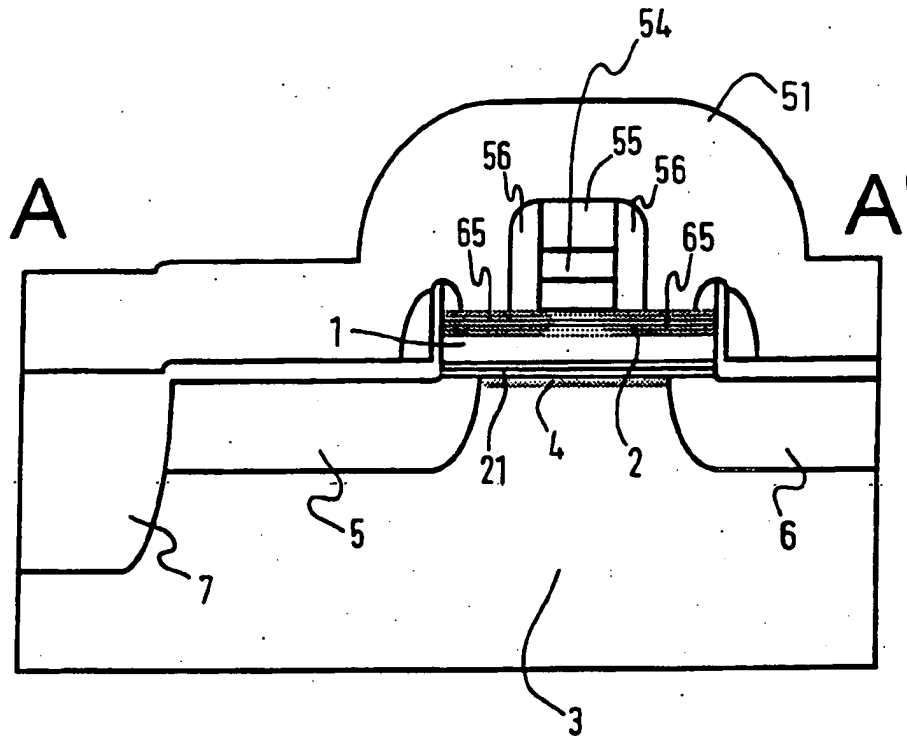
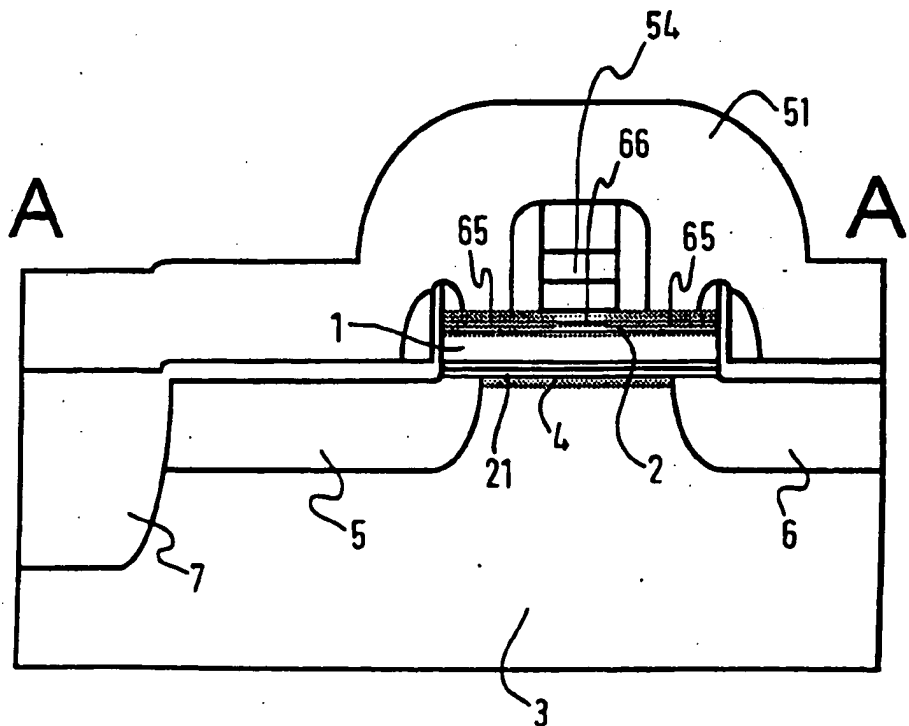


FIG. 28



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